

<b>Search Notes</b> 				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/769,385	CHEN ET AL.	
				Examiner	Art Unit	
				Elena Tsoy	1762	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner		DATE	EXAM
427	402, 419.1; 419.2; 419.3	2/2/2008	ET	EAST/EPO, JPO,Derwent	2/2/2008	ET
<i>updated</i> 6/06 ET <i>updated</i> 9/06 ET <i>updated</i> 2/07 ET <i>updated</i> 6/07 ET <i>updated</i> 9/07 ET						
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			